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Bib Data Sheet

CONFIRMATION NO. 8915

SERIAL NUMBER 09/942,213	FILING DATE 08/30/2001 RULE	CLASS 438	GROUP ART UNIT 2812	ATTORNEY DOCKET NO. 501.40475X00
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** CONTINUING DATA ***** *none JS*** FOREIGN APPLICATIONS ***** *JS*

JAPAN 2001-185773 06/20/2001

IF REQUIRED, FOREIGN FILING LICENSE GRANTED

** 10/08/2001

Foreign Priority claimed	<input checked="" type="checkbox"/> yes <input type="checkbox"/> no	STATE OR COUNTRY JAPAN	SHEETS DRAWING 19	TOTAL CLAIMS 18	INDEPENDENT CLAIMS 3
35 USC 119 (a-d) conditions met	<input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Met after Allowance				
Verified and Acknowledged	<i>John Gray</i> Examiner's Signature	JS Initials			

ADDRESS

020457

TITLE

Method and apparatus for inspecting a semiconductor device

FILING FEE RECEIVED 840	FEES: Authority has been given in Paper No. _____ to charge/credit DEPOSIT ACCOUNT No. _____ for following:	<input type="checkbox"/> All Fees <input type="checkbox"/> 1.16 Fees (Filing) <input type="checkbox"/> 1.17 Fees (Processing Ext. of time) <input type="checkbox"/> 1.18 Fees (Issue) <input type="checkbox"/> Other _____ <input type="checkbox"/> Credit
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